







# TEST REPORT

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<p><b>1. Client</b></p> <ul style="list-style-type: none"> <li>◦ Name : IPX Corporation</li> <li>◦ Address : 5F ,98, Hannam-daero, Yongsan-gu, Seoul, Republic of Korea</li> <li>◦ Date of Receipt : 2023-12-27</li> </ul> <p><b>2. Use of Report</b> : Certification</p> <p><b>3. Name of Product / Model</b> : LF_LENINI_23 DESK CHARGER / 8809954704642</p> <p><b>4. Manufacturer / Country of Origin</b> : Huizhou OJD Technology Co., Ltd / China</p> <p><b>5. FCC ID</b> : 2AQT SIPX-23CE-CHA01</p> <p><b>6. Date of Test</b> : 2024-01-09 to 2024-02-01</p> <p><b>7. Location of Test</b> : <input checked="" type="checkbox"/> Permanent Testing Lab <input type="checkbox"/> On Site Testing (Address:65, Sinwon-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea)</p> <p><b>8. Test method used</b> : 47 CRF Part 1.1310</p> <p><b>9. Test Result</b> : Refer to the test result in the test report</p>		
<p>Affirmation</p>	<p>Tested by</p> <p>Name : Minki Kim (Signature)</p> 	<p>Technical Manager</p> <p>Name : Heesu Ahn (Signature)</p> 
<p style="text-align: right;">2024-02-27</p>		
<p style="text-align: center;"><b>Eurofins KCTL Co.,Ltd.</b></p>		
<p>As a test result of the sample which was submitted from the client, this report does not guarantee the whole product quality. This test report should not be used and copied without a written agreement by Eurofins KCTL Co.,Ltd.</p>		

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## REPORT REVISION HISTORY

Date	Revision	Page No
2024-02-07	Originally issued	-
2024-02-23	Updated	1, 3, 9, 10, 11, 19 ~ 30
2024-02-27	Updated	9, 10

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Note. The report No. KR24-SRF0010-A is superseded by the report No. KR24-SRF0010-B.

## General remarks for test reports

### Statement concerning the uncertainty of the measurement systems used for the tests

(may be required by the product standard or client)

Internal procedure used for type testing through which traceability of the measuring uncertainty has been established:

#### Procedure number, issue date and title:

Calculations leading to the reported values are on file with the testing laboratory that conducted the testing.

Statement not required by the standard or client used for type testing

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## 1. General information

Client : IPX Corporation  
Address : 5F ,98, Hannam-daero, Yongsan-gu, Seoul, Republic of Korea  
Manufacturer : Huizhou OJD Technology Co., Ltd  
Address : 7F, Building 20, Zoina Hi-tech Industrial Park, No.6 Xinhua Avenue,  
Chenjiang Street, Zhongkai High-tech Zone, Huizhou city, Guangdong  
Province, China  
Laboratory : Eurofins KCTL Co.,Ltd.  
Address : 65, Sinwon-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea  
Accreditations : FCC Site Designation No: KR0040, FCC Site Registration No: 687132  
VCCI Registration No. : R-20080, G-20078, C-20059, T-20056  
CAB Identifier: KR0040  
ISED Number: 8035A  
KOLAS No.: KT231

## 2. Device information

Equipment under test : LF\_LENINI\_23 DESK CHARGER  
Model : 8809954704642  
Modulation technique : ASK  
Frequency range : 110 ~ 205 kHz (WPT)  
Power source : DC 9 V  
Antenna specification : Coil antenna  
Software version : V1.0.0  
Hardware version : V1.0.0  
Test device serial No. : N/A  
Operation temperature : -10 °C ~ 40 °C

## 2.1. Companion device information

Equipment	Manufacturer	Model	Serial No.
Smart Phone	Samsung Electronics Co., Ltd	SM-G996N	N/A

## 2.2. Frequency/channel operations

This device contains the following capabilities:  
 WPT

Frequency (kHz)
110 ~ 205

Table 2.2.1. WPT System

## 2.3. Worst-Case configuration and mode

Test Case	Description
1	<b>Charging from EUT to Phone            (&lt;10% Power Charging, Fast charging mode)</b>
2	Charging from EUT to Phone (50~55% Power Charging, Fast charging mode)
3	Charging from EUT to Phone (90~95% Power Charging, Fast charging mode)

According to current client device's battery level, test results are different. Because the test result were worst when the battery level was below 10%, tests were performed when the battery level was below 10%.(Client device)

Test results of case 1 is worst, so this test report described test case 1.

## 2.4. Normal and extreme test conditions

- Ambient Conditions

Item	Temperature [°C]	Relative Humidity [%]
Requirement for tests	15 to 35	20 to 75
Ambient Conditions	21	51

- Test Conditions

Test Condition	Temperature [°C]	Voltage [V]
NTNV	21	DC 9

Note 1 : N:Normal T:Temperature V:Voltage

### 3. Measurement uncertainty

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.10-2013.

All measurement uncertainty values are shown with a coverage factor of  $k=2$  to indicated a 95 % level of confidence. The measurement data shown herein meets or exceeds the  $U_{CISPR}$  measurement uncertainty values specified in CISPR 16-4-2 and thus, can be compared directly to specified limits to determine compliance.

Parameter	Expanded Uncertainty ( $\pm$ )	
E-Field	3 kHz ~ 10 MHz	1.0 %
H-Field	3 kHz ~ 10 MHz	1.3 %



## 4. RF Exposure

### 4.1. FCC Regulation

This document is prepared to show compliance with the RF Exposure requirements as required in §1.1310 of the FCC rules and Regulations.

The limit for Maximum Permissible Exposure (MPE), specified in FCC §1.1310, is listed in Table 1-1. According to FCC §1.1310: the criteria listed in the following table shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in §1.1307(b).

Table 1 – Limits for Maximum Permissible Exposure (MPE)

Frequency Range (MHz)	Electric Field Strength [V/m]	Magnetic Field Strength [A/m]	Power Density [mW/cm <sup>2</sup> ]	Averaging Time [minute]
(A) Limits for Occupational / Controlled Exposure				
0.3 ~ 3.0	614	1.63	*100	6
3.0 ~ 30	1842/f	4.89/f	*900/f <sup>2</sup>	6
30 ~ 300	61.4	0.163	1.0	6
300 ~ 1 500	/	/	f/300	6
1 500 ~ 15 000	/	/	5	6
(B) Limits for General Population / Uncontrolled Exposure				
0.3 ~ 1.34	614	1.63	*100	30
1.34 ~ 30	824/f	2.19/f	*180/f <sup>2</sup>	30
30 ~ 300	27.5	0.073	0.2	30
300 ~ 1 500	/	/	f/1 500	30
1 500 ~ 15 000	/	/	1.0	30

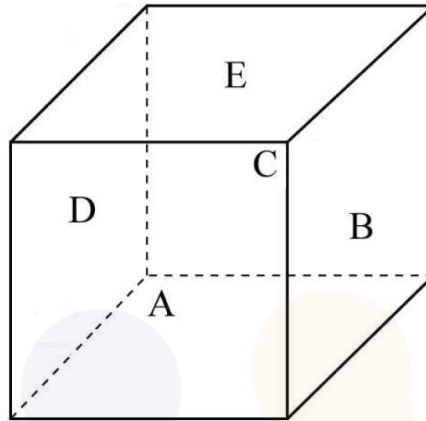
*f*=frequency in MHz, \* = plane-wave equivalent power density

Per the guidance of KDB 680106, the E-field and H-field limits shown in the table above are extended down to 100 kHz

## 4.2. Test set-up

### 4.2.1. Isotropic Probe test setup

The measurement probe (EHP-200A) is a regular hexahedron and supports 3-axis (X, Y and Z) isotropic probe.



- A: Front of measurement probe
- B: Right of measurement probe
- C: Rear of measurement probe
- D: Left of measurement probe
- E: Top of measurement probe

\*Bottom of measurement probe is not used to measure RF exposure condition owing to connection with a stick.

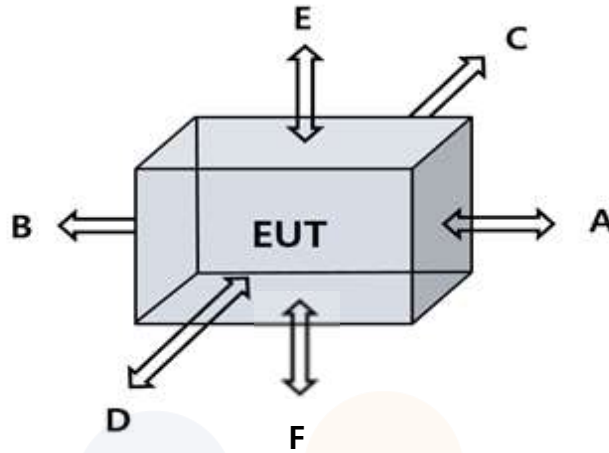
At 0 cm distance, measurement isotropic probe was investigated by rotating the probe through various angles for one of the EUT's sides as below.

Measurement Point	A	B	C	D	E
Direction	Front	Right	Rear	Left	Top
Measurement Point	A to B	B to C	C to D	D to A	N/A
Direction	Front to Right	Right to Rear	Rear to Left	Left to Front	-
Measurement Point	A to E	B to E	C to E	D to E	N/A
Direction	Front to Top	Right to Top	Rear to Top	Left to Top	-

When the worst angle among all angles was found, RF exposure measurement should be adjusted from worst angle.



#### 4.2.2. EUT Test setup



- 1) Testing was performed with a calibrated field probe.
- 2) Measurement was performed on each side of the EUT as described per below table.
- 3) EUT and Tag distances were all verified at 0(Direct), 3, 6, and 9 mm.  
 The worst condition is 3 mm.

A	B	C	D	E	F
Front	Rear	Right	Left	Top	Bottom

\* F is not the product surface.

<b>Measurement Probe</b>	EHP-200A (Manufacturer: Narda)
<b>Measurement Method</b>	Distance measurement [3 mm]
<b>Measurement Distance</b>	Surface of the EUT to the center of the probe.

**Equipment approval considerations item 5.b) of KDB 680106 D01 v04**

- (1) Power transfer frequency is less than 1 MHz.
  - ▶ This device is operates at a frequency of 110 kHz ~ 205 kHz
  
- (2) The output power from each transmitting element (e.g., coil) is less than or equal to 15 watts.
  - ▶ DC 9.0 V condition / Output power from each primary coil :
    - Top Coil : 5, 7.5, 10, 15 watts
    - Bottom Coil : 5, 7.5, 10, 15 watts
  
- (3) A client device providing the maximum permitted load is placed in physical contact with the transmitter  
 (i.e., the surfaces of the transmitter and client device enclosures need to be in physical contact)
  - ▶ The client device is placed directly in contact with the transmitter.
  
- (4) Only § 2.1091-Mobile exposure conditions apply  
 (i.e., this provision does not cover § 2.1093-Portable exposure conditions).
  - ▶ This device is mobile exposure condition.
  
- (5) The E-field and H-field strengths, at and beyond 20 cm surrounding the device surface, are demonstrated to be less than 50% of the applicable MPE limit, per KDB 447498, Table 1. These measurements shall be taken along the principal axes of the device, with one axis oriented along the direction of the estimated maximum field strength, and for three points per axis or until a 1/d (inverse distance from the emitter structure) field strength decay is observed. Symmetry considerations may be used for test reduction purposes. The device shall be operated in documented worst-case compliance scenarios (i.e., the ones that lead to the maximum field components), and while all the radiating structures (e.g., coils or antennas) that by design can simultaneously transmit are energized at their nominal maximum power.
  - ▶ The EUT field strength levels < 50 % of the MPE limit 1.63 A/m  
 0.076 A/m (Max) < 0.815 A/m
  
- (6) For systems with more than one radiating structure, the conditions specified in (5) must be met when the system is fully loaded (i.e., clients absorbing maximum power available), and with all the radiating structures operating at maximum power at the same time, as per design conditions. If the design allows one or more radiating structures to be powered at a higher level while other radiating structures are not powered, then those cases must be tested as well. For instance, a device may use three RF coils powered at 5 W, or one coil powered at 15 W: in this case, both scenarios shall be tested.
  - ▶ The transfer system includes two primary coils(Top, Bottom).

**4.3. Test configuration (Description of test mode)**

Test case configuration is reported as below.

Test Case	Description
1	<b>Charging from EUT to Phone (&lt;10% Power Charging, Fast charging mode)</b>
2	Charging from EUT to Phone (50~55% Power Charging, Fast charging mode)
3	Charging from EUT to Phone (90~95% Power Charging, Fast charging mode)

Test results of case 1 is worst, so this test report described test case 1.

## 4.4. Test Result

**4.4.1. Test mode: test result of rotating the probe through various angles**  
**Distance : 15cm surrounding the device and 20cm above the top surface.**

- Result : TOP\_5W

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	1.291 6	2.199 1	<b>2.451 8</b>	1.490 9	1.222 1	1.965 2	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	0.15 19	0.085 8	0.108 5	<b>0.180 5</b>	0.118 3	0.128 7	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	<b>28230</b>	23828	14871	21245	27096	25621	15913	25943	15498	27584	26539	24041	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	0.1125	0.1598	0.1605	<b>0.2794</b>	0.1416	0.1407	0.1402	0.1743	0.1336	0.1055	0.2206	0.2345	1.63

**Note:**

- Worst position of isotropic probe: E-field = A to C-side, H-field = A to F-side.

**- Result : TOP\_7.5W**

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	1.235 9	2.349 7	<b>2.535 9</b>	1.455 6	1.102 0	1.992 4	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	0.139 4	0.084 3	0.116 0	0.171 4	<b>1.380 0</b>	0.084 5	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	29148	23820	14506	22344	26357	29584	15438	26635	<b>32406</b>	27203	28522	31034	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	0.1534	0.1719	0.1688	<b>0.3210</b>	0.1469	0.1948	0.1348	0.1769	0.2440	0.1064	0.2350	0.2076	1.63

**Note:**

- Worst position of isotropic probe: E-field = C to E-side, H-field = A to F-side.

**- Result : TOP\_10W**

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	1.281 1	2.277 1	<b>2.548 2</b>	1.428 3	1.185 6	1.638 1	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	0.149 2	0.084 3	0.115 8	<b>0.171 7</b>	0.155 3	0.080 8	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	29606	23351	14489	23370	27491	<b>3.3507</b>	15449	26670	3.1985	27179	28831	25011	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	0.1587	0.1694	0.1674	0.2749	0.1476	<b>0.4078</b>	0.1398	0.1798	0.2470	0.1040	0.2414	0.2427	1.63

**Note:**

- Worst position of isotropic probe: E-field = B to D-side, H-field = B to D-side.

**- Result : TOP\_15W**

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	1.241 6	2.216 7	<b>2.513 0</b>	1.412 1	1.140 4	1.625 0	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	0.140 5	0.086 7	0.112 2	<b>0.171 8</b>	0.151 4	0.078 9	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	29339	23604	14543	23846	25768	28557	15431	25500	<b>32315</b>	27243	28232	23810	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	0.1550	0.1815	0.1689	<b>0.3107</b>	0.1352	0.1894	0.1385	0.1696	0.2534	0.1039	0.2398	0.2326	1.63

**Note:**

- Worst position of isotropic probe: E-field = C to E-side, H-field = A to F-side.

**- Result : BOTTOM\_5W**

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	2.852 0	4.199 4	<b>4.681 1</b>	2.900 7	2.521 1	0.358 9	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	<b>0.735 8</b>	0.311 0	0.224 9	0.576 1	0.684 2	0.237 7	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	32181	26389	1.8069	2.1245	3.1953	3.3692	1.7051	2.9030	<b>3.4758</b>	2.8935	3.1595	2.5824	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	0.2661	0.3326	0.2287	0.2794	0.2450	<b>0.3938</b>	0.1697	0.2883	0.2476	0.1995	0.2530	0.3013	1.63

**Note:**

- Worst position of isotropic probe: E-field = C-side, H-field = A-side.

**- Result : BOTTOM\_7.5W**

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	2.917 1	4.326 0	<b>4.670 9</b>	2.928 8	2.547 6	3.722 4	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	<b>0.722 6</b>	0.316 2	0.225 0	0.577 9	0.680 9	0.233 6	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	32499	25684	15482	21837	32032	<b>3.3507</b>	1.7012	2.9317	2.6418	2.8842	3.0978	2.5507	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	0.2732	0.3358	0.2301	0.3162	0.2374	<b>0.4078</b>	0.1684	0.2889	0.2754	0.2019	0.2551	0.3338	1.63

**Note:**

- Worst position of isotropic probe: E-field = C-side, H-field = A-side.



**- Result : BOTTOM\_10W**

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	2.928 1	4.313 0	<b>4.670 9</b>	2.922 7	2.580 8	3.720 2	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	<b>0.720 3</b>	0.311 9	0.225 0	0.578 0	0.680 6	0.238 6	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	33416	25528	16089	22023	32156	32982	16912	29246	<b>35866</b>	29182	30016	26078	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	02807	03382	02288	02983	02397	<b>04010</b>	01688	02893	02581	02002	02533	02958	1.63

**Note:**

- Worst position of isotropic probe: E-field = C-side, H-field = A-side.

**- Result : BOTTOM\_15W**

- E-field measurement results (Sides of probe)

Frequency [kHz]	E-field Measurement [V/m]						Limits [V/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	2.903 3	4.301 7	<b>4.647 4</b>	2.874 5	2.531 2	3.739 4	614.00

- H-field measurement results (Sides of probe)

Frequency [kHz]	H-field Measurement [A/m]						Limits [A/m]
	Probe rotation						
	A	B	C	D	E	F	
112.5	<b>0.720 9</b>	0.311 7	0.224 7	0.580 5	0.676 7	0.242 5	1.63

- E-field measurement results (Rotation of probe)

Frequency [kHz]	E-field Measurement [V/m]												Limits [V/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	3.3890	26328	1.5890	2.2970	3.2127	3.3531	1.6693	2.9095	<b>3.4740</b>	2.9089	2.9762	2.3810	614.00

- H-field measurement results (Rotation of probe)

Frequency [kHz]	H-field Measurement [A/m]												Limits [A/m]
	Probe rotation												
	AtoC	AtoD	AtoE	AtoF	BtoC	BtoD	BtoE	BtoF	CtoE	CtoF	DtoE	DtoF	
112.5	0.2922	0.3593	0.2309	0.2952	0.2445	<b>0.4038</b>	0.1702	0.2763	0.2583	0.1972	0.2512	0.2326	1.63

**Note:**

- Worst position of isotropic probe: E-field = C-side, H-field = A-side.

**4.4.2. Test mode: Test result of EUT's sides about the distance**

**Distance : 15cm surrounding the device and 20cm above the top surface.**

**- Result : TOP\_5W**

**- E-field measurement results**

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>2.976 1</b>	2.475 5	2.736 9	2.564 1	2.088 0	2.545 9	614.00

**- H-field measurement results**

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.228 4</b>	0.095 2	0.157 3	0.112 5	0.077 3	0.090 0	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : A-side, H-field : A-side) of isotropic probe.

**- Result : TOP\_7.5W**

**- E-field measurement results**

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	2.690 4	2.097 0	2.785 8	<b>2.824 0</b>	2.391 8	1.996 9	614.00

**- H-field measurement results**

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.229 7</b>	0.090 5	0.156 1	0.119 8	0.072 2	0.090 4	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : D-side, H-field : A-side) of isotropic probe.

**- Result : TOP\_10W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	2.510 8	<b>2.720 5</b>	2.459 0	2.009 1	2.673 6	2.106 9	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.129 7	<b>0.164 8</b>	0.080 1	0.110 7	0.097 8	0.148 0	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : B-side, H-field : B-side) of isotropic probe.

**- Result : TOP\_15W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>3.028 2</b>	2.054 6	2.886 1	2.789 4	2.255 0	2.078 3	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.225 0</b>	0.091 9	0.168 5	0.122 5	0.085 0	0.090 4	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : A-side, H-field : A-side) of isotropic probe.

**- Result : BOTTOM\_5W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>5.114 7</b>	4.271 6	4.744 7	5.103 4	4.243 3	3.252 4	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.536 6</b>	0.525 4	0.096 6	0.108 0	0.334 4	0.208 1	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : A-side, H-field : A-side) of isotropic probe.

**- Result : BOTTOM\_7.5W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	4.810 8	4.294 6	4.322 5	<b>5.061 3</b>	4.035 1	3.045 9	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.526 6</b>	0.506 6	0.119 7	0.105 9	0.328 1	0.204 5	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : D-side, H-field : A-side) of isotropic probe.

**- Result : BOTTOM\_10W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	4.770 5	4.315 0	4.463 6	<b>5.091 1</b>	3.989 0	3.073 0	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.519 2	<b>0.522 7</b>	0.104 7	0.111 6	0.328 0	0.204 3	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : D-side, H-field : B-side) of isotropic probe.

**- Result : BOTTOM\_15W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	4.748 1	4.361 5	4.387 0	<b>5.154 9</b>	3.900 0	3.066 4	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.512 1	<b>0.496 6</b>	0.104 3	0.112 0	0.335 0	0.198 2	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : D-side, H-field : B-side) of isotropic probe.

**Distance : 22<sub>cm</sub> surrounding the device and 20<sub>cm</sub> above the top surface.**

**- Result : TOP\_5W**

**- E-field measurement results**

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.852 2	2.016 4	<b>2.324 5</b>	1.866 6	2.267 2	2.121 8	614.00

**- H-field measurement results**

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.098 4	0.178 8	0.132 7	0.123 9	0.127 8	<b>0.192 1</b>	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : C-side, H-field : F-side) of isotropic probe.

**- Result : TOP\_7.5W**

**- E-field measurement results**

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.735 8	<b>1.977 5</b>	1.602 2	1.550 6	1.282 5	0.842 1	614.00

**- H-field measurement results**

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.104 2	0.175 8	0.131 8	0.126 4	0.131 7	<b>0.193 6</b>	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : B-side, H-field : F-side) of isotropic probe.

**- Result : TOP\_10W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.474 7	<b>2.084 9</b>	1.412 1	1.691 7	1.203 2	0.960 0	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.068 5	0.115 0	0.055 4	0.061 6	0.105 1	<b>0.129 9</b>	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : B-side, H-field : F-side) of isotropic probe.

**- Result : TOP\_15W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>1.927 3</b>	1.821 3	1.586 8	1.704 5	1.258 4	0.987 9	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.104 9	0.194 4	0.131 0	0.113 3	0.133 4	<b>0.199 3</b>	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : A-side, H-field : F-side) of isotropic probe.



**- Result : BOTTOM\_5W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.888 4	<b>2.652 9</b>	2.634 1	2.610 4	2.266 6	2.391 8	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.269 3	<b>0.313 0</b>	0.069 2	0.089 7	0.093 8	0.079 8	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : B-side, H-field : B-side) of isotropic probe.

**- Result : BOTTOM\_7.5W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>2.803 8</b>	2.585 3	2.596 0	2.026 0	2.179 8	2.664 5	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.302 5	<b>0.309 1</b>	0.071 3	0.074 9	0.098 2	0.081 4	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : A-side, H-field : B-side) of isotropic probe.

**- Result : BOTTOM\_10W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>2.903 1</b>	2.625 6	2.587 4	2.612 1	2.182 2	2.805 7	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.308 1	<b>0.311 0</b>	0.070 6	0.075 1	0.097 0	0.083 5	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : A-side, H-field : B-side) of isotropic probe.

**- Result : BOTTOM\_15W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>2.877 9</b>	2.573 1	2.601 2	2.613 7	2.147 9	2.597 3	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.312 3</b>	0.297 3	0.078 4	0.075 0	0.078 4	0.080 9	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : A-side, H-field : A-side) of isotropic probe.

**Distance : 24<sub>cm</sub> surrounding the device and 20<sub>cm</sub> above the top surface.**

**- Result : TOP\_5W**

**- E-field measurement results**

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.624 4	1.644 4	<b>1.994 4</b>	1.540 9	1.991 6	1.809 9	614.00

**- H-field measurement results**

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.085 3	<b>0.168 8</b>	0.124 6	0.099 5	0.105 8	0.166 7	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : C-side, H-field : B-side) of isotropic probe.

**- Result : TOP\_7.5W**

**- E-field measurement results**

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.696 0	1.840 8	1.311 6	1.175 8	<b>2.391 8</b>	0.838 8	614.00

**- H-field measurement results**

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.114 0	<b>0.190 6</b>	0.124 0	0.112 5	0.110 9	0.158 2	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : E-side, H-field : B-side) of isotropic probe.

**- Result : TOP\_10W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.290 7	<b>1.730 7</b>	1.106 0	1.377 4	1.019 7	0.724 7	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.058 9	0.089 7	0.048 8	0.053 4	0.089 3	<b>0.115 2</b>	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : B-side, H-field : F-side) of isotropic probe.

**- Result : TOP\_15W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	1.6669	<b>1.8638</b>	1.2930	1.0703	1.0671	0.8284	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	0.109 1	0.154 3	0.124 5	0.112 7	0.104 9	<b>0.158 8</b>	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : B-side, H-field : F-side) of isotropic probe.

**- Result : BOTTOM\_5W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	2.136 9	2.104 8	2.105 4	2.122 5	<b>2.144 4</b>	2.150 0	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.255 7</b>	0.222 5	0.061 8	0.067 1	0.054 2	0.070 3	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : E-side, H-field : A-side) of isotropic probe.

**- Result : BOTTOM\_7.5W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	2.127 5	2.142 4	2.096 6	2.173 1	<b>2.215 2</b>	2.109 2	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.257 8</b>	0.215 5	0.061 5	0.064 9	0.066 3	0.068 5	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : E-side, H-field : A-side) of isotropic probe.

**- Result : BOTTOM\_10W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	2.121 7	2.089 6	2.130 6	2.169 6	<b>2.539 4</b>	2.047 4	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.256 5</b>	0.194 6	0.063 9	0.064 0	0.068 5	0.070 1	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : E-side, H-field : A-side) of isotropic probe.

**- Result : BOTTOM\_15W**

- E-field measurement results

Distance [cm]	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	2.130 6	2.065 1	<b>4.387 0</b>	2.149 2	2.119 6	2.230 3	614.00

- H-field measurement results

Distance [cm]	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
15(~10%)	112.5	<b>0.258 5</b>	0.157 8	0.061 5	0.063 8	0.069 7	0.068 5	1.63

**Note:**

- Above RF exposure measurement was performed considering worst position (E-field : C-side, H-field : A-side) of isotropic probe.

## 5. Measurement equipment

Equipment Name	Manufacturer	Model No.	Serial No.	Next Cal. Date
E&H Field Probe	narda	EHP-200A	170WX81015	25.01.30

**End of test report**

